**Product data sheet** 

# 1. General description

Planar passivated high commutation three quadrant triac in a SOT1292 (IITO3P) package intended for use in circuits where high static and dynamic dV/dt and high dI/dt can occur. This "series BT" triac will commutate the full RMS current at the maximum rated junction temperature ( $T_{j(max)} = 150~^{\circ}$ C) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

## 2. Features and benefits

- High current TRIAC
- · 3Q technology for improved noise immunity
- High commutation capability with maximum false trigger immunity
- High immunity to false turn-on by dV/dt
- High junction operating temperature capability (T<sub>i(max)</sub> = 150 °C)
- High voltage capability
- · Least sensitive gate for highest noise immunity
- · Low thermal resistance
- · Planar passivated for voltage ruggedness and reliability
- Triggering in three quadrants only
- Insulated tab rated at 2500 V rms

# 3. Applications

- Applications subject to high temperature (T<sub>i(max)</sub> = 150 °C)
- · High current / high surge applications
- · High power / industrial controls e.g. heating, motors, lighting

## 4. Quick reference data

Table 1. Quick reference data

| Symbol  | Parameter  | Conditions   |   | Min | Тур | Max | Unit |
|---|--|--|---|-----|-----|-----|------|
| $V_{DRM}$   | repetitive peak off-<br>state voltage                                      |  |   | -   | -   | 800 | V    |
| I <sub>T(RMS)</sub>                                       | RMS on-state current   | full sine wave; $T_{mb} \le 105 ^{\circ}\text{C}$ ; Fig. 1; Fig. 2; Fig. 3                     |   | _   | -   | 45  | Α    |
| I <sub>TSM</sub> non-repetitive peak on-<br>state current | non-repetitive peak on-<br>state current                                   | full sine wave; $T_{j(init)} = 25 \text{ °C}$ ;<br>$t_p = 20 \text{ ms}$ ; $Fig. 4$ ; $Fig. 5$ |   | -   | -   | 450 | А    |
|   | full sine wave; $T_{j(init)} = 25 \text{ °C}$ ;<br>$t_p = 16.7 \text{ ms}$ |  | - | -   | 495 | А   |      |
| Tj  | junction temperature   |  |   | -   | -   | 150 | °C   |
| Static characteristics                                    |  |  |   |     |     |     |      |

| Symbol                | Parameter                             | Conditions  | Min  | Тур | Max | Unit |
|-----------------------|---------------------------------------|---|------|-----|-----|------|
| I <sub>GT</sub>       | gate trigger current                  | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$<br>$T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$                           | -    | -   | 50  | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$<br>$T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$                   | -    | -   | 50  | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-};$<br>$T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$                   | -    | -   | 50  | mA   |
| I <sub>H</sub>        | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>  | -    | -   | 80  | mA   |
| V <sub>T</sub>        | on-state voltage                      | I <sub>T</sub> = 63.6 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>   | -    | -   | 1.7 | V    |
| Dynamic cha           | racteristics                          |   |      |     |     |      |
| dV <sub>D</sub> /dt   | rate of rise of off-state voltage     | $V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit                    | 1000 | -   | -   | V/µs |
| dl <sub>com</sub> /dt | rate of change of commutating current | $V_D$ = 400 V; $T_j$ = 150 °C; $I_{T(RMS)}$ = 20 A; $dV_{com}/dt$ = 20 V/ $\mu$ s; (snubberless condition); gate open circuit | 15   | -   | -   | A/ms |

# 5. Pinning information

## **Table 2. Pinning information**

| Pin | Symbol | Description             | Simplified outline | Graphic symbol |
|-----|--------|-------------------------|--------------------|----------------|
| 1   | T1     | main terminal 1         |                    | T2—T1          |
| 2   | T2     | main terminal 2         |                    | G<br>sym051    |
| 3   | G      | gate                    | 0                  | Symost         |
| mb  | n.c.   | mounting base; isolated |                    |                |
|     |        |                         |                    |                |
|     |        |                         | V V V<br>1 2 3     |                |
|     |        |                         | IITO3P (SOT1292)   |                |

# 6. Ordering information

# **Table 3. Ordering information**

| Type number   | Package |  |         |  |  |  |
|---------------|---------|--|---------|--|--|--|
|               | Name    | Description  | Version |  |  |  |
| BTA445Z-800BT | IITO3P  | plastic single-ended through-hole package; isolated heatsink mounted; 1 mounting hole; 3-lead TO3P | SOT1292 |  |  |  |

# 7. Limiting values

### **Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol              | Parameter                                | Conditions   | Min | Max    | Unit |
|---------------------|--|--|-----|--------|------|
| $V_{DRM}$           | repetitive peak off-state voltage        |  | -   | 800    | V    |
| I <sub>T(RMS)</sub> | RMS on-state current                     | full sine wave; $T_{mb} \le 105 ^{\circ}\text{C}$ ; Fig. 1; Fig. 2; Fig. 3 | -   | 45     | Α    |
| I <sub>TSM</sub>    | non-repetitive peak on-<br>state current | full sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 20 ms;<br>Fig. 4; Fig. 5    | -   | 450    | Α    |
|                     |  | full sine wave; T <sub>j(init)</sub> = 25 °C; t <sub>p</sub> = 16.7 ms     | -   | 495    | Α    |
| l <sup>2</sup> t    | I <sup>2</sup> t for fusing              | t <sub>p</sub> = 10 ms; sine-wave pulse                                    | -   | 1012.5 | A²s  |
| dl <sub>T</sub> /dt | rate of rise of on-state current         | I <sub>G</sub> = 0.2 A   | -   | 150    | A/µs |
| I <sub>GM</sub>     | peak gate current                        | t <sub>p</sub> = 20 μs   | -   | 8      | Α    |
| P <sub>GM</sub>     | peak gate power                          | t <sub>p</sub> = 20 μs   | -   | 40     | W    |
| P <sub>G(AV)</sub>  | average gate power                       |  | -   | 1      | W    |
| T <sub>stg</sub>    | storage temperature                      |  | -40 | 150    | °C   |
| T <sub>j</sub>      | junction temperature                     |  | -   | 150    | °C   |

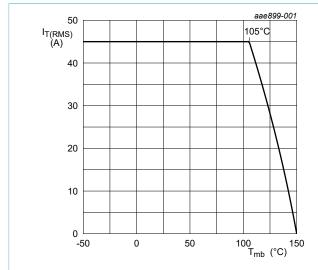
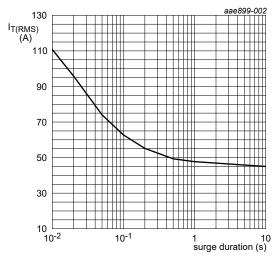


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



f = 50 Hz;  $T_{mb} = 105 \text{ °C}$ 

Fig. 2. RMS on-state current as a function of surge duration; maximum values

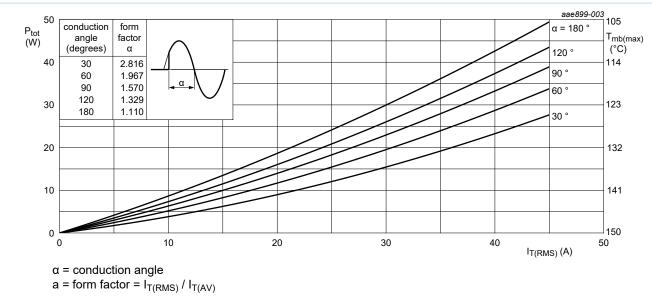


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

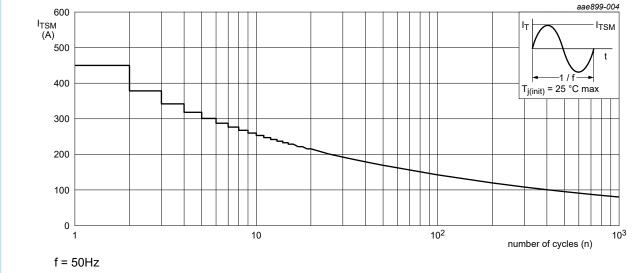
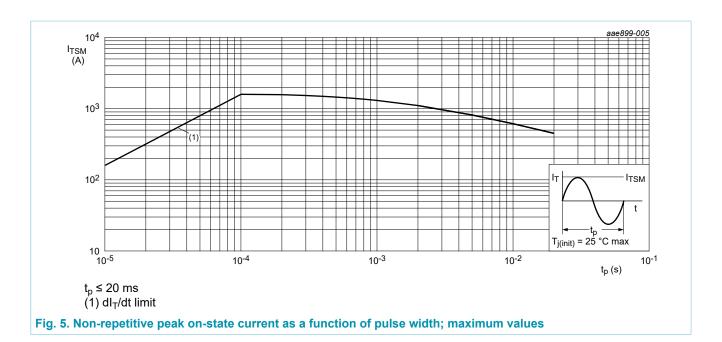


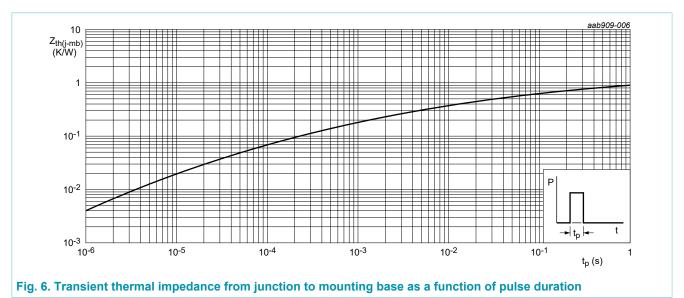
Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



# 8. Thermal characteristics

**Table 5. Thermal characteristics** 

| Symbol                | Parameter  | Conditions  | Min | Тур | Max | Unit |
|-----------------------|--|-------------|-----|-----|-----|------|
| R <sub>th(j-mb)</sub> | thermal resistance<br>from junction to<br>mounting base    | Fig. 6      | -   | -   | 0.9 | K/W  |
| R <sub>th(j-a)</sub>  | thermal resistance<br>from junction to<br>ambient free air | in free air | -   | 50  | -   | K/W  |



# 9. Isolation characteristics

## **Table 6. Isolation characteristics**

| Symbol                  | Parameter             | Conditions   | Min | Тур | Max  | Unit |
|-------------------------|-----------------------|--|-----|-----|------|------|
| V <sub>isol</sub> (RMS) | RMS isolation voltage | from all terminals to external heatsink; sinusoidal waveform; clean and dust free; $50 \text{ Hz} \le f \le 60 \text{ Hz}$ ; $RH \le 65 \%$ ; $T_{mb} = 25 ^{\circ}\text{C}$ | -   | -   | 2500 | V    |

# 10. Characteristics

#### **Table 7. Characteristics**

| Symbol                | Parameter                             | Conditions  | Min  | Тур  | Max | Unit |
|-----------------------|---------------------------------------|---|------|------|-----|------|
| Static chara          | acteristics                           |   |      |      |     |      |
| I <sub>GT</sub>       | gate trigger current                  | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G+;$<br>$T_j = 25 \text{ °C; } Fig. 7$   | -    | -    | 50  | mA   |
|                       |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$<br>$T_j = 25 \text{ °C; } Fig. 7$   | -    | -    | 50  | mA   |
|                       |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2- \text{ G-;}$<br>$T_j = 25 \text{ °C; } Fig. 7$  | -    | -    | 50  | mA   |
| IL                    | latching current                      | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$<br>$T_j = 25 \text{ °C}; Fig. 8$   | -    | -    | 70  | mA   |
|                       |                                       | $V_D = 12 \text{ V; } I_G = 0.1 \text{ A; } T2 + G-;$<br>$T_j = 25 \text{ °C; } Fig. 8$   | -    | -    | 160 | mA   |
|                       |                                       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$<br>$T_j = 25 ^{\circ}\text{C}; \text{ Fig. 8}$   | -    | -    | 70  | mA   |
| I <sub>H</sub>        | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>  | -    | -    | 80  | mA   |
| V <sub>T</sub>        | on-state voltage                      | I <sub>T</sub> = 63.6 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>   | -    | -    | 1.7 | V    |
| V <sub>GT</sub>       | gate trigger voltage                  | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>   | -    | 8.0  | 1.3 | V    |
|                       |                                       | V <sub>D</sub> = 400 V; T <sub>j</sub> = 150 °C; <u>Fig. 11</u>   | 0.2  | 0.45 | -   | V    |
| l <sub>D</sub>        | off-state current                     | V <sub>D</sub> = 800 V; T <sub>j</sub> = 25 °C  | -    | -    | 10  | μA   |
|                       |                                       | V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C   | -    | -    | 2   | mA   |
| Dynamic ch            | naracteristics                        |   | ,    |      |     |      |
| dV <sub>D</sub> /dt   | rate of rise of off-state voltage     | $V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit  | 1000 | -    | -   | V/µs |
| dl <sub>com</sub> /dt | rate of change of commutating current | $V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 20 \text{ A};$<br>$dV_{com}/dt = 20 \text{ V/}\mu\text{s}; (snubberless condition); gate open circuit$ | 15   | -    | -   | A/ms |

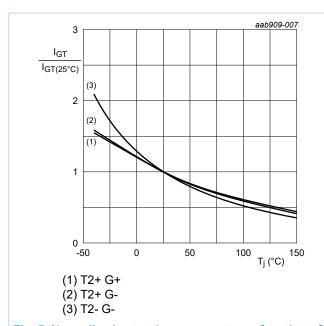


Fig. 7. Normalized gate trigger current as a function of junction temperature

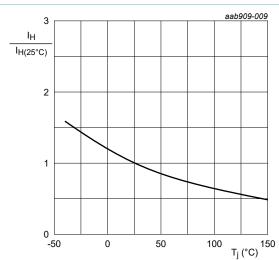


Fig. 9. Normalized holding current as a function of junction temperature

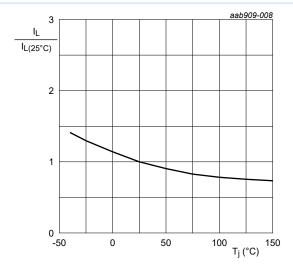
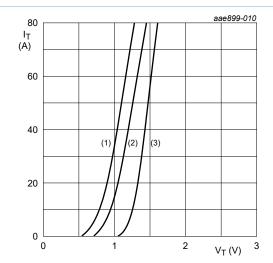
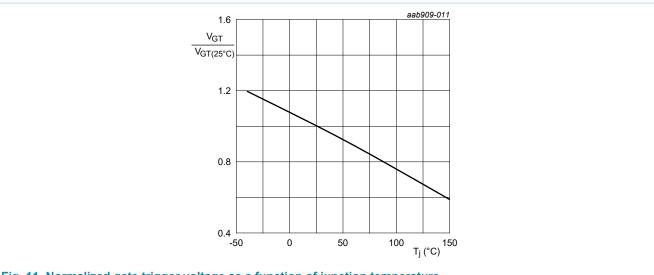


Fig. 8. Normalized latching current as a function of junction temperature

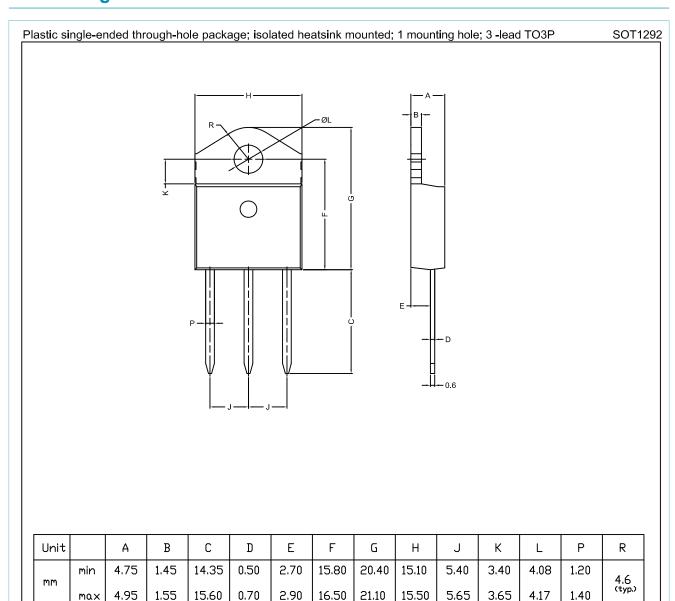


 $V_o$  = 0.887 V;  $R_s$  = 0.0067 Ω (1)  $T_j$  = 150 °C; typical values (2)  $T_j$  = 150 °C; maximum values (3)  $T_j$  = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage



# 11. Package outline



| OUTLINE |     | REFEREN | EUROPEAN | ISSUE DATE |            |            |
|---------|-----|---------|----------|------------|------------|------------|
| VERSION | IEC | JEDEC   | EIAJ     |            | PROJECTION | ISSUE DATE |
| S0T1292 |     | -       |          |            |            |            |

Fig. 12. Package outline IITO3P (SOT1292)

# 12. Legal information

#### **Data sheet status**

| Document status [1][2]               | Product status [3] | Definition  |
|--------------------------------------|--------------------|---|
| Objective<br>[short] data<br>sheet   | Development        | This document contains data from the objective specification for product development. |
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For more information, please visit: http://www.ween-semi.com For sales office addresses, please send an email to: salesaddresses@ween-semi.com Date of release: 20 July 2017

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